

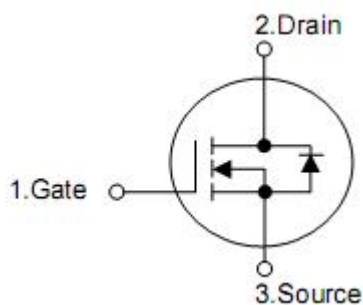
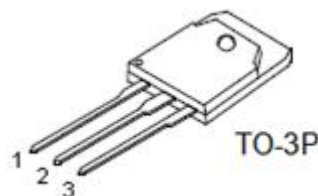
1. Description

This Power MOSFET is produced using KIA semi`s advanced super-junction technology. This advanced technology has been especially tailored to minimize conduction loss, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for AC/DC power conversion in switching mode operation for higher efficiency.

2. Features

- $R_{DS(ON)}=0.16\Omega@V_{GS}=10\text{ V}$
- Low gate charge (typical 70nC)
- High ruggedness
- Fast switching
- 100%avalanche tested
- Improved dv/dt capability

3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source

4. Absolute maximum ratings

(T_c = 25 °C , unless otherwise specified)

Parameter		Symbol	Ratings	Units
Drain-source voltage		V _{DSS}	650	V
Gate-source voltage		V _{GSS}	±30	V
Drain current continuous	T _c =25°C	I _D	20*	A
	T _c =100°C		10*	A
Drain current pulsed (note1)		I _{DM}	62*	A
Avalanche energy	Repetitive (note1)	E _{AR}	1	mJ
	Single pulse (note2)	E _{AS}	485	mJ
Avalanche current (note1)		I _{AR}	20	A
Peak diode recovery dv/dt (note3)		dv/dt	4.5	V/ns
Total power dissipation	T _c =25°C	P _D	208	W
	Derate above 25°C		1.66	W/°C
Operating and storage temperature range		T _J , T _{STG}	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		T _L	300	°C

* Drain current limited by maximum junction temperature

5. Thermal characteristics

Parameter	Symbol	Rating	Unit
Thermal resistance, Junction-ambient	R _{thJA}	62	°C/W
Thermal resistance, case-to-sink typ.	R _{thJS}	-	°C/W
Thermal resistance, Junction-case	R _{thJC}	0.6	°C/W

6. Electrical characteristics

 (T_J=25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Off characteristics						
Drain-source breakdown voltage	T _J =25°C	V _{GS} =0V, I _D =250μA,	650	-	-	V
	T _J =150°C		-	700	-	V
Zero gate voltage drain current	I _{DSS}	V _{DS} =650V, V _{GS} =0V	-	-	1	μA
		V _{DS} =480V, T _C =125°C	-	-	10	μA
Gate-body leakage current	Forward	V _{GS} =30V, V _{DS} =0V	-	-	100	nA
	Reverse	V _{GS} =-30V, V _{DS} =0V	-	-	-100	nA
Breakdown voltage temperature coefficient	ΔBV _{DSS} /ΔT _J	I _D =250μA, referenced to 25°C	-	0.6	-	V/°C
On characteristics						
Gate threshold voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250μA	2.0	-	4.5	V
Static drain-source on-resistance	R _{DS(ON)}	V _{GS} =10V, I _D =12A	-	0.16	0.19	Ω
Forward transconductance	g _{FS}	V _{DS} =40V, I _D =12A (note4)	-	16	-	S
Dynamic characteristics						
Input capacitance	C _{ISS}	V _{DS} =25V, V _{GS} =0V, f=1MHz	-	1440	-	pF
Output capacitance	C _{OSS}		-	300	-	pF
Reverse transfer capacitance	C _{RSS}		-	10	-	pF
Switching characteristics						
Turn-on delay time	t _{D(ON)}	V _{DD} =400V, I _D =12A, R _G =20Ω (note4,5)	-	25	-	ns
Rise time	t _R		-	55	-	ns
Turn-off delay time	t _{D(OFF)}		-	70	-	ns
Fall time	t _F		-	40	-	ns
Total gate charge	Q _G	V _{DS} =480V, I _D =20A, V _{GS} =10V (note4,5)	-	70	90	nC
Gate-source charge	Q _{GS}		-	7.8	-	nC
Gate-drain charge	Q _{GD}		-	9	-	nC
Drain-source diode characteristics						
Drain-source diode forward voltage	V _{SD}	V _{GS} =0V, I _{SD} =20A	-	1	1.5	V
Continuous drain-source current	I _S		-	-	20	A
Pulsed drain-source current	I _{SM}		-	-	60	A
Reverse recovery time	t _{RR}	V _{GS} =0V, I _S =20A, di _F /dt=100A/μs (note4)	-	475	-	ns
Reverse recovery charge	Q _{RR}		-	5.8	-	μC
Peak reverse recovery current	I _{RRM}		-	35	-	A

Note: 1. Repetitive rating : pulse width limited by maximum junction temperature

 2. L= 10.5mH, I_{AS}= 10A, V_{DD}=150V, starting T_J=25°C

 3. I_{SD}≤I_D, di/dt≤200A/μs, V_{DD}≤BV_{DSS}, starting T_J=25°C

4. Pulse test : pulse width≤300μs, duty cycle≤2%

5. Essentially independent of operating temperature

7. Test circuits and waveforms

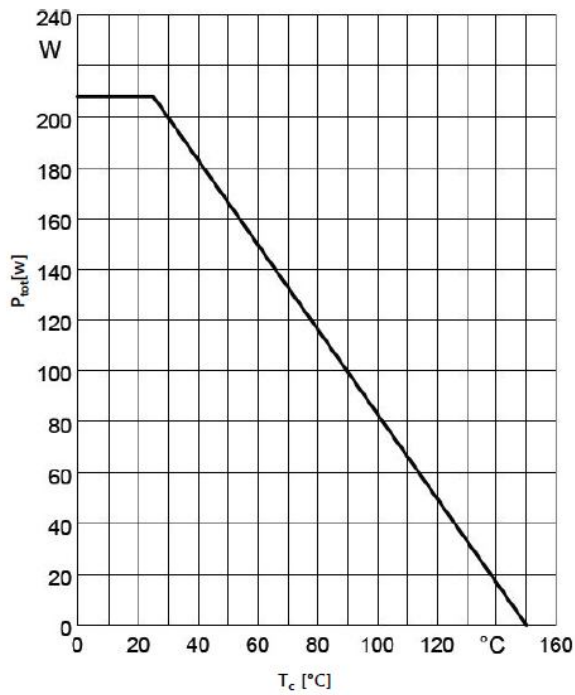


Figure 1: Power dissipation

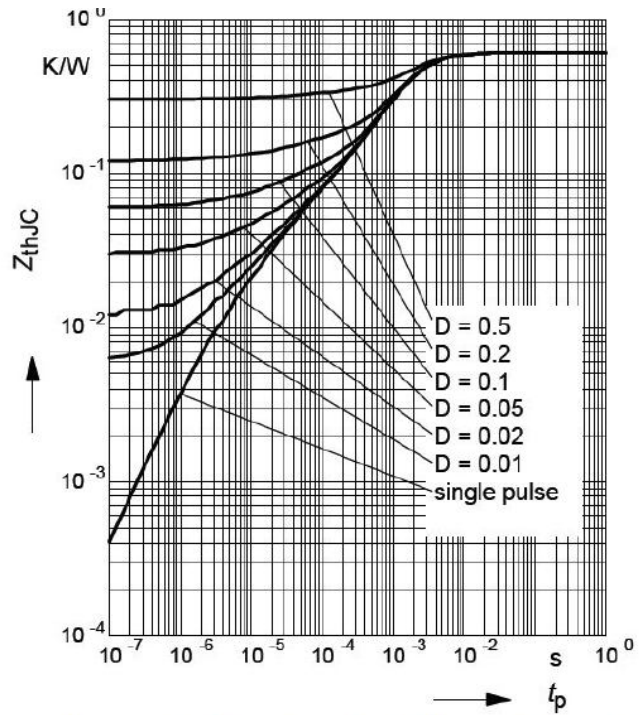
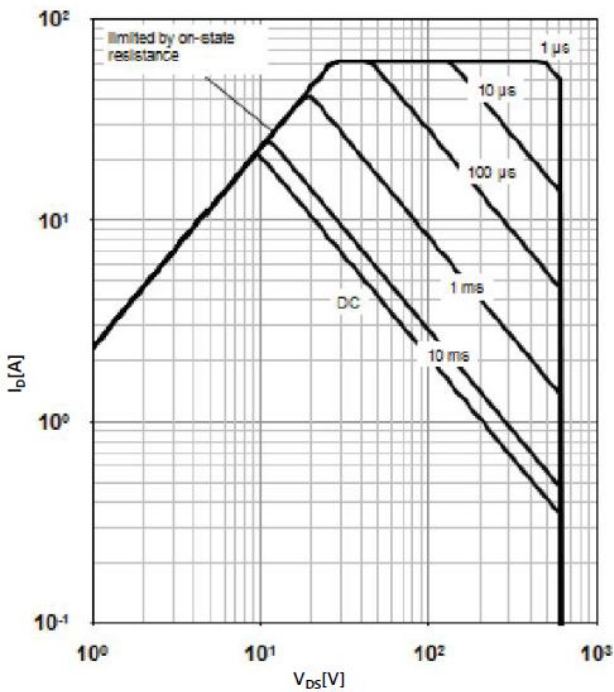
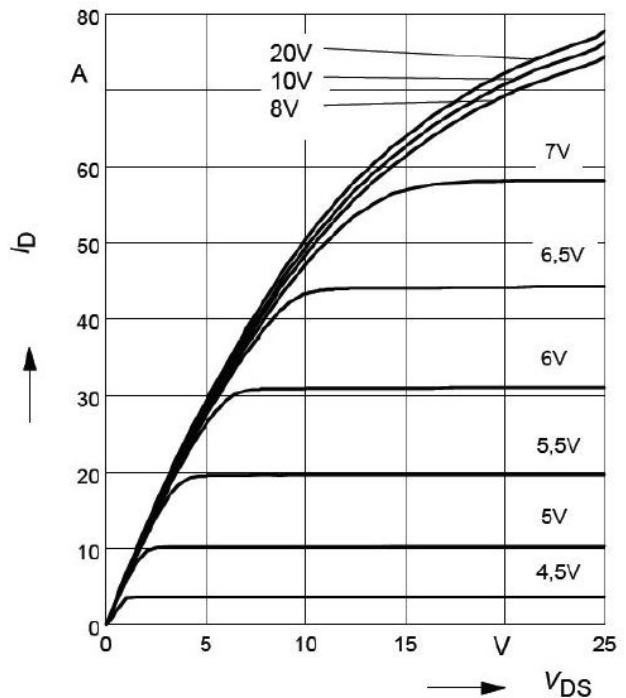


Figure 2: Max. transient thermal impedance



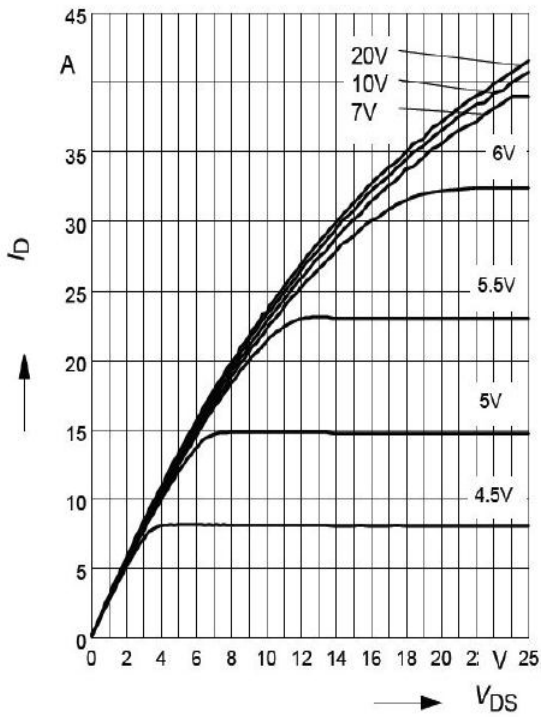
$I_D = f(V_{DS})$; $T_C = 25^\circ\text{C}$; $V_{GS} > 7\text{V}$; $D = 0$; parameter t_n

Figure 3: Safe operating area $TC=25^\circ\text{C}$



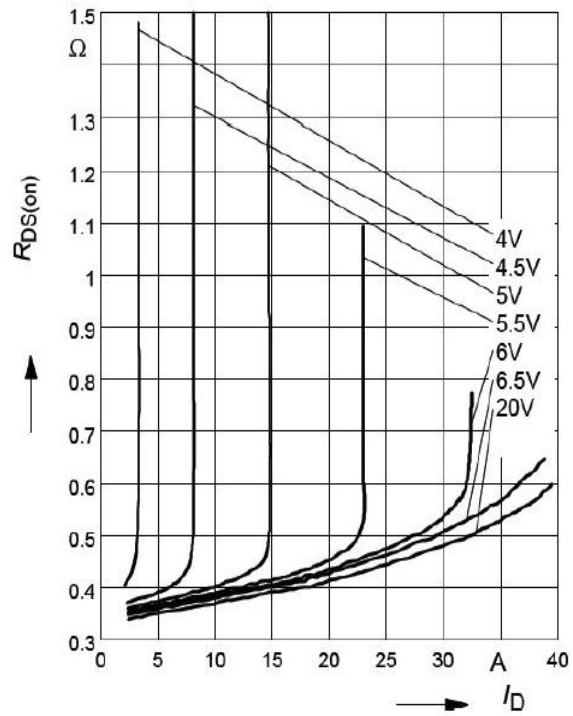
$I_D = f(V_{DS})$; $T_C = 25^\circ\text{C}$; parameter $t_n = 10\mu\text{s}$, V_{GS}

Figure 4: Typ. output characteristic



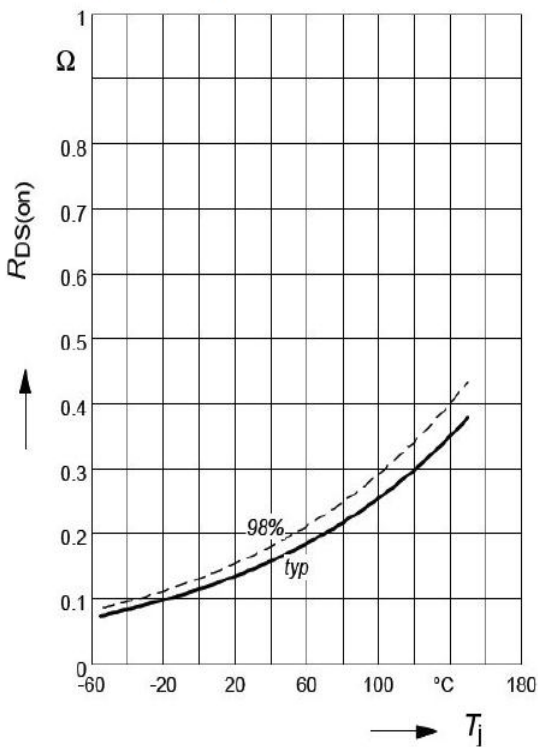
$I_D = f(V_{DS}); T_J = 150^\circ\text{C}; \text{parameter } t_p = 10\mu\text{s}, V_{GS}$

Figure 5: Typ. output characteristic



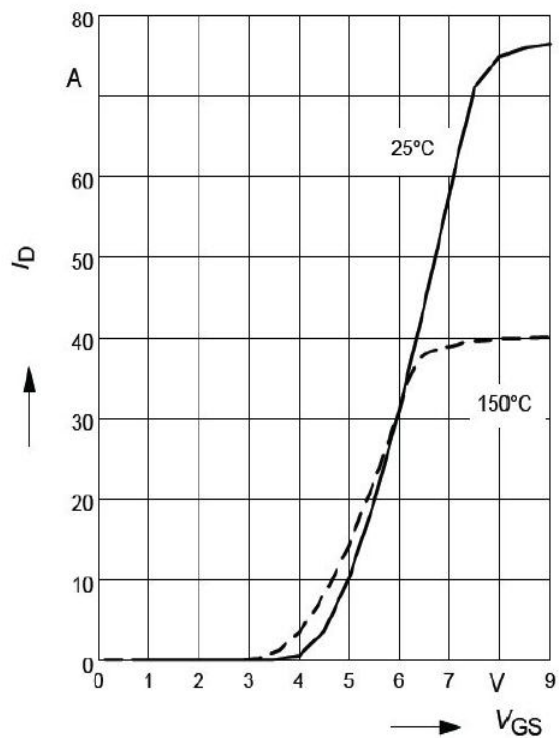
$R_{Dson} = f(I_D); T_J = 150^\circ\text{C}; \text{parameter } V_{GS}$

Figure 6: Typ. Drain-Source on resistance



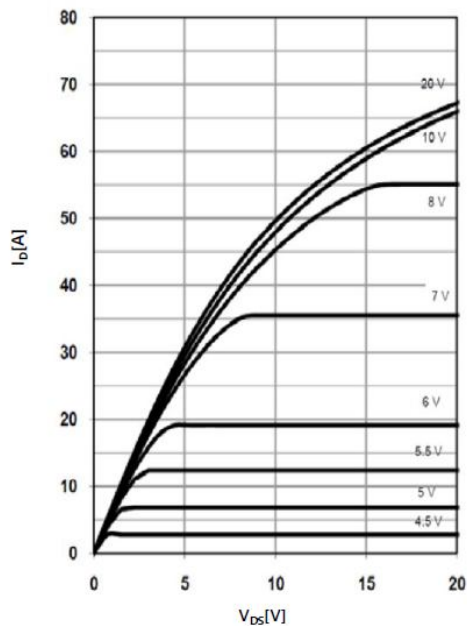
$R_{Dson} = f(T_J); T_J = 150^\circ\text{C}; \text{parameter } I_D = 12\text{A } V_{GS} = 10\text{V}$

Figure 7: Typ. Drain-Source on resistance

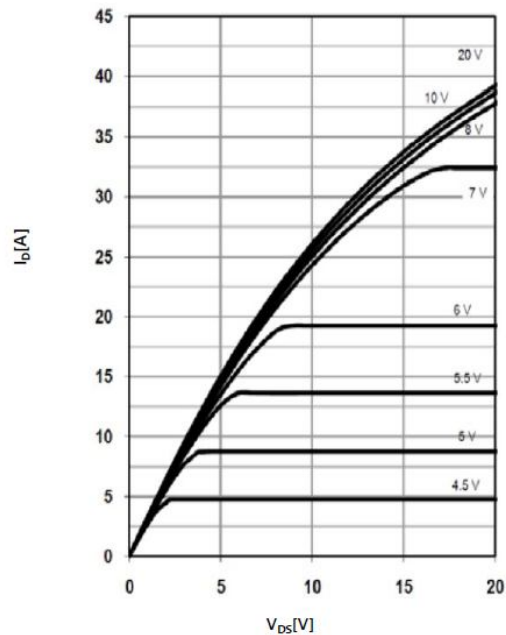


$I_D = f(V_{GS}); V_{DS} > 2 \times I_D \times R_{DS(on)max}; \text{parameter } t_p = 10\mu\text{s}$

Figure 8: Typ. Transfer characteristic

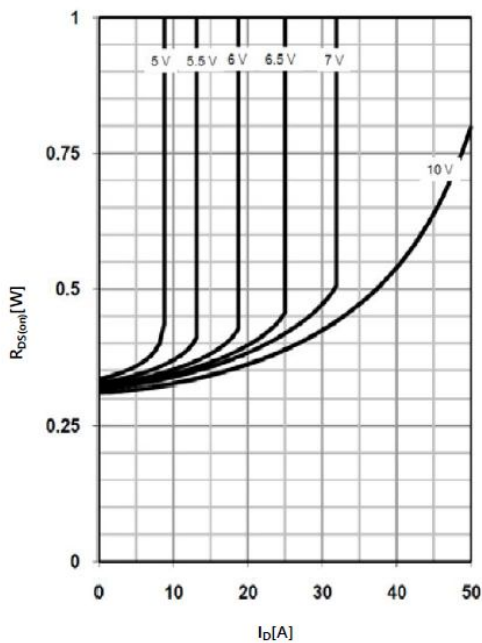


$I_D = f(V_{DS}); T_J = 25\text{ °C}; \text{ parameter: } V_{GS}$

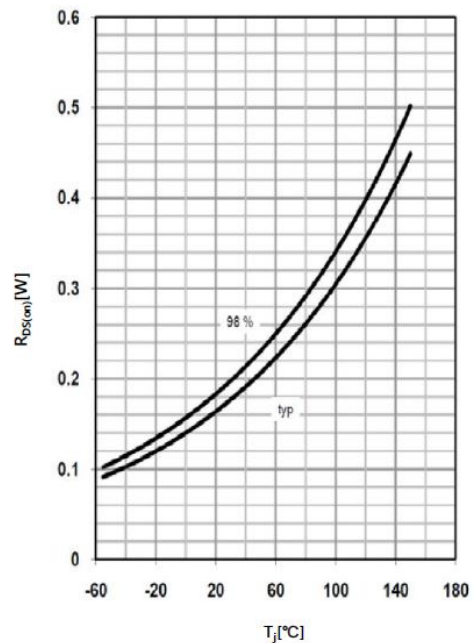


$I_D = f(V_{DS}); T_J = 125\text{ °C}; \text{ parameter: } V_{GS}$

Figure 9: Typ. output characteristics $T_J = 25\text{ °C}$ Figure 10: Typ. output characteristics $T_J = 125\text{ °C}$



$R_{DS(on)} = f(I_D); T_J = 125\text{ °C}; \text{ parameter: } V_{GS}$



$R_{DS(on)} = f(T_J); I_D = 7.3\text{ A}; V_{GS} = 10\text{ V}$

Figure 11: Typ. drain-source on-state resistance Figure 12: Typ. drain-source on-state resistance

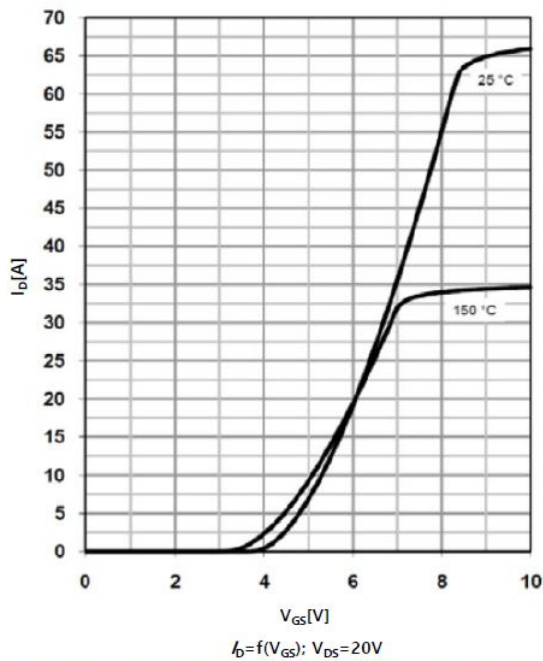


Figure 13: Typ. transfer characteristics

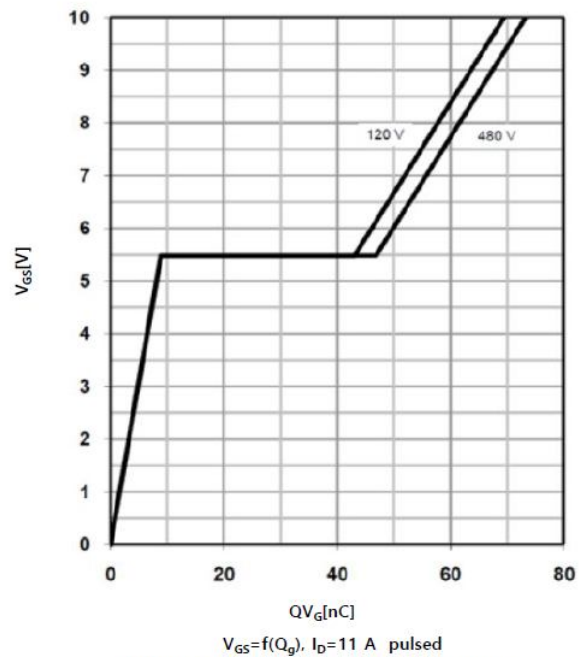


Figure 14: Typ. gate charge

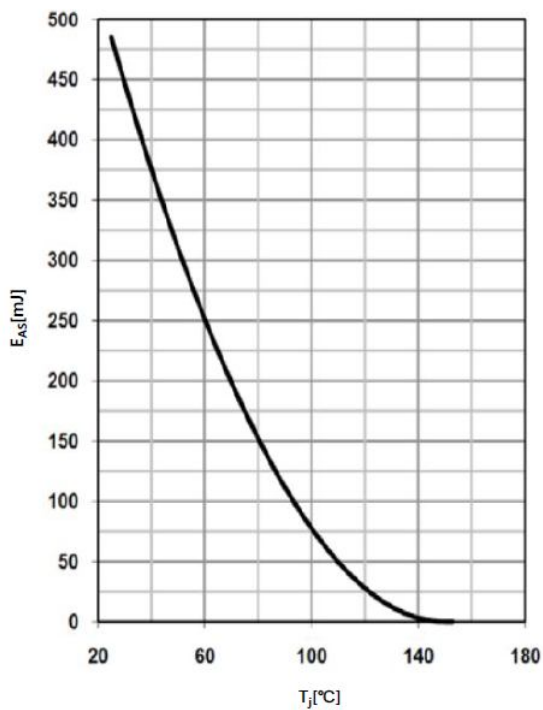


Figure 15: Avalanche energy

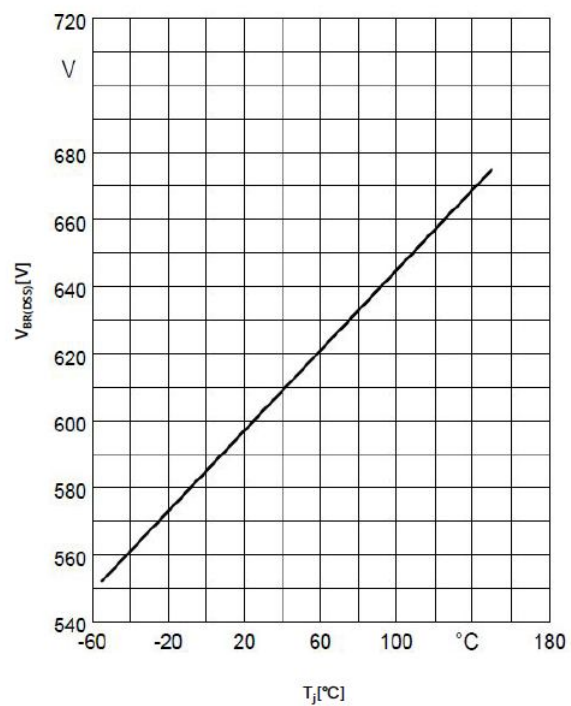


Figure 16: Drain-source breakdown voltage

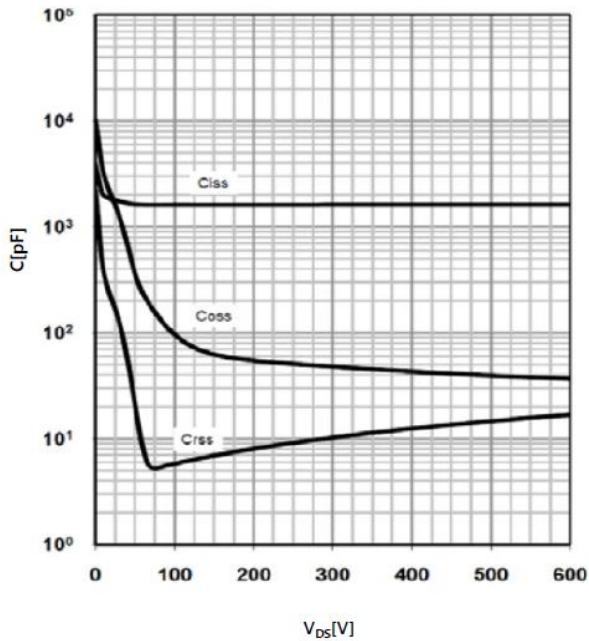


Figure 17: Typ. capacitances

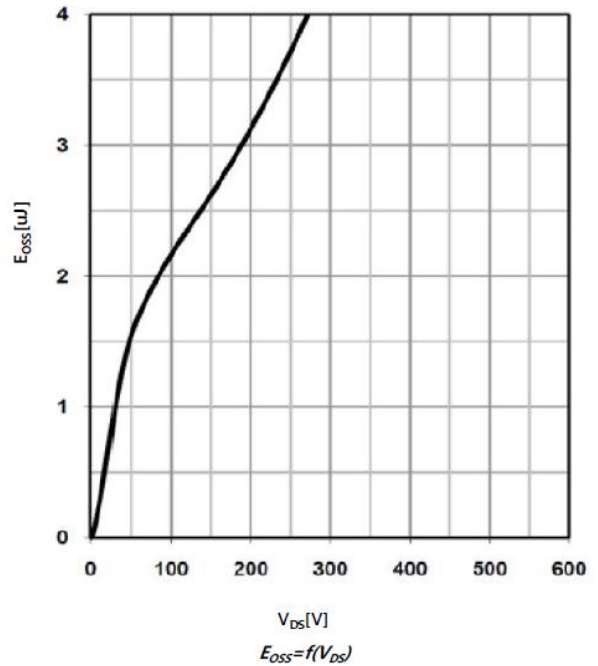


Figure 18: Typ. *C_{oss}* stored energy

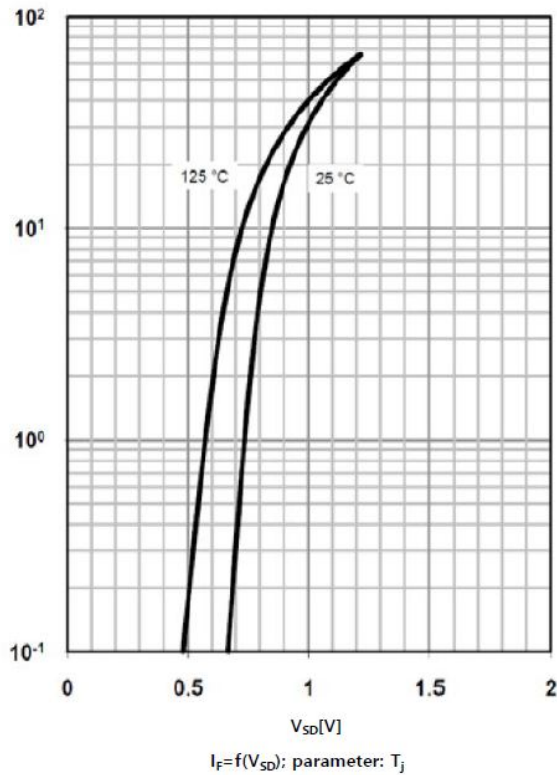


Figure 19: Forward characteristics of reverse diode